Se	arch	Notes	

Application/Control No.	Applicant(s)/Patent und Reexamination	er
09/826,009	NAKAHARA ET AL.	
Examiner	Art Unit	
Christopher Onuaku	2621	

	SEAR	CHED	
Class	Subclass	Date	Examiner
.386	46,52,55,9 4-96,68- 70,104,10 5,	5/23/2007	coo
	125,126		
360	13,60	5/24/2007	coo
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
386	95,125	6/9/2007	coo
	- I		

SEARCH (INCLUDING SEAR		")
	DATE	EXMR
Thai Tran 386	5/23/2007	coo
Andy Sniezek 360	5/24/2007	coo
Interference search done	6/9/2007	coo
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